

STFI260N6F6

N-channel 60 V, 0.0024 Ω 80 A STripFET™ VI DeepGATE™ Power MOSFET in I²PAKFP package

Datasheet — preliminary data

Features

Order codes	V _{DSS}	R _{DS(on)} max	I _D
STFI260N6F6	60 V	< 0.003 Ω	80 A

- Fully insulated and low profile package with increased creepage path from pin to heatsink plate
- Low gate charge
- Very low on-resistance
- High avalanche ruggedness

Application

Switching applications

Description

This device is an N-channel Power MOSFET developed using the 6th generation of STripFETTM DeepGATETM technology, with a new gate structure. The resulting Power MOSFET exhibits the lowest $R_{DS(on)}$ in all packages.

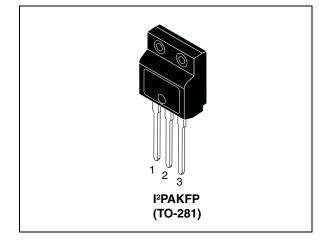


Figure 1. Internal schematic diagram

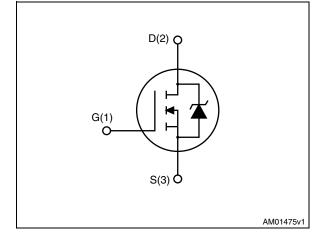


Table 1. Device summary

Order codes	Marking	Package	Packaging
STFI260N6F6	260N6F6	l²PAK (TO-281)	Tube

April 2012

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1 Electrical ratings

Table 2.	Absolute	maximum	ratings
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Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage	60	V
V _{GS}	Gate-source voltage	± 20	V
I _D	Drain current (continuous) at $T_C = 25 \ ^{\circ}C$	80 ⁽¹⁾	Α
I _D	Drain current (continuous) at $T_C = 100 \ ^{\circ}C$	80 ⁽¹⁾	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	320	Α
P _{TOT}	Total dissipation at $T_C = 25 \ ^{\circ}C$	41.7	W
	Derating factor	0.28	W/°C
T _{stg}	Storage temperature	55 to 175	°C
Тj	Operating junction temperature	- 55 to 175	

1. Current limited by package.

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	3.6	°C/W
R _{thj-a}	Thermal resistance junction-ambient max	62.5	°C/W
т	Maximum lead temperature for soldering purpose	300	°C



2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage (V _{GS} = 0)	I _D = 250 μA	60			v
1	Zero gate voltage	V _{DS} = 60 V			1	μA
IDSS	Drain current (V _{GS} = 0)	V _{DS} = 60 V, T _C =125 °C			100	μA
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 20 V			± 100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	2		4	V
R _{DS(on)}	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 60 \text{ A}$		2.4	3	mΩ

Table 4. On/off states

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance			11400		pF
C _{oss}	Output capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} = 0	-	1100	-	pF
C _{rss}	Reverse transfer capacitance	$V_{GS} = 0$		400		pF
Qg	Total gate charge	V _{DD} = 30 V, I _D = 120 A,		183		nC
Q _{gs}	Gate-source charge	$V_{DD} = 30 \text{ V}, \text{ I}_{D} = 120 \text{ A},$ $V_{GS} = 10 \text{ V}$	-	53	-	nC
Q _{gd}	Gate-drain charge	(see Figure 14)		41		nC

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on delay time Rise time	$V_{DD} = 30 \text{ V}, \text{ I}_{D} = 60 \text{ A}$ $R_{G} = 4.7 \Omega V_{GS} = 10 \text{ V}$	-	31.4 165	-	ns ns
t _{d(off)} t _f	Turn-off-delay time Fall time	(see Figure 13)	-	144.4 62.6	-	ns ns



Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
I _{SD}	Source-drain current		-		120	А
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		480	А
V _{SD} ⁽²⁾	Forward on voltage	$I_{SD} = 120 \text{ A}, V_{GS} = 0$	-		1.1	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 120 \text{ A}, V_{DD} = 48 \text{ V}$ di/dt = 100 A/µs, $T_j = 150 \text{ °C}$ (see Figure 15)	-	55.6 116 3.8		ns nC A

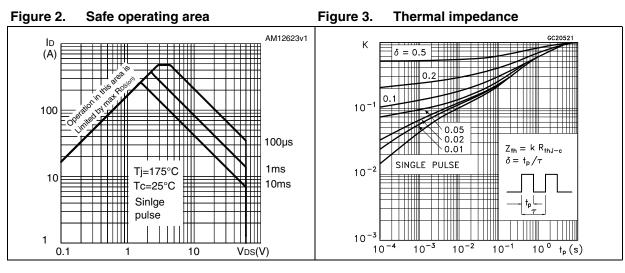
Table 7.Source drain diode

1. Current limited by package.

2. Pulsed: pulse duration = 300 μ s, duty cycle 1.5%

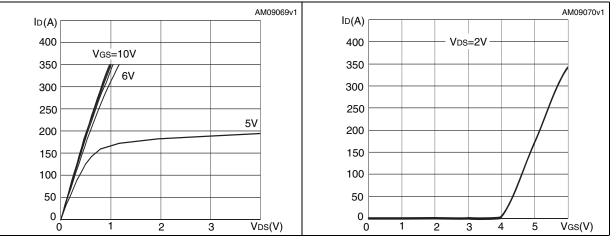


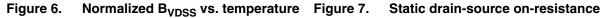
2.1 Electrical characteristics (curves)











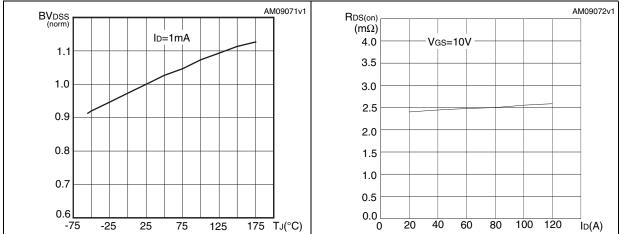




Figure 8. Gate charge vs. gate-source voltage



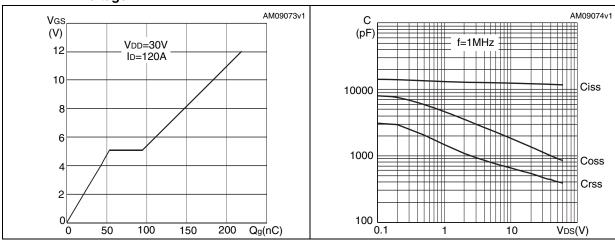


Figure 10. Normalized gate threshold voltage Figure 11. vs. temperature

re 11. Normalized on-resistance vs. temperature

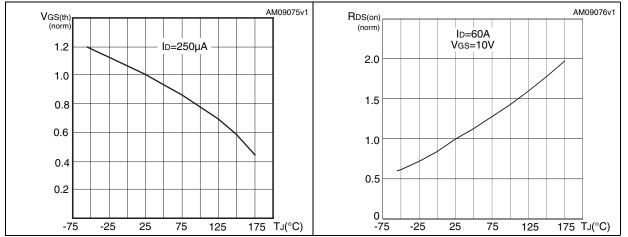
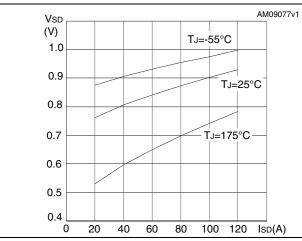


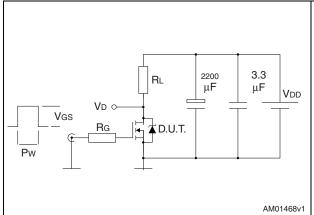
Figure 12. Source-drain diode forward characteristics





3 Test circuits

Figure 13. Switching times test circuit for resistive load



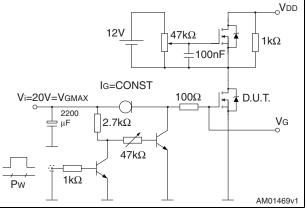
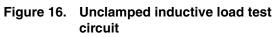


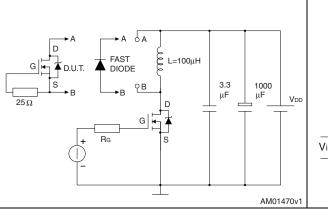
Figure 14. Gate charge test circuit

Figure 15. Test circuit for inductive load switching and diode recovery times

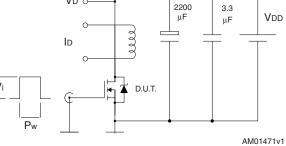


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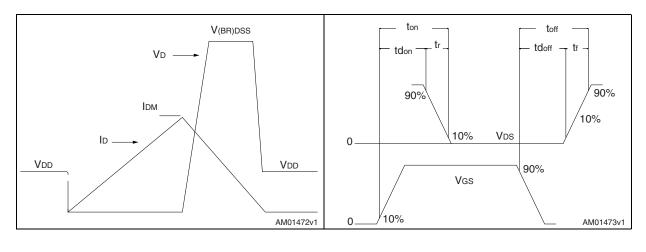
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4 Package mechanical data

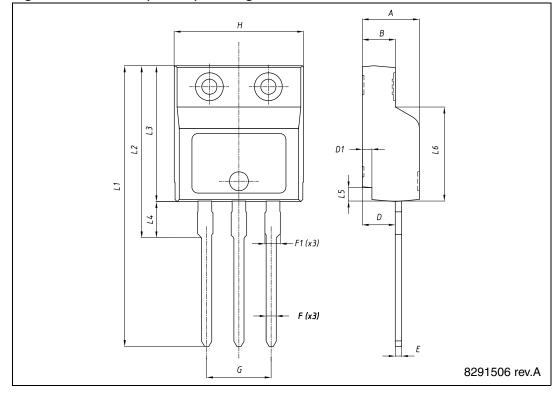
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Dim.		mm	
Dini.	Min.	Тур.	Max.
А	4.40		4.60
В	2.50		2.70
D	2.50		2.75
D1	0.65		0.85
E	0.45		0.70
F	0.75		1.00
F1			1.20
G	4.95	-	5.20
н	10.00		10.40
L1	21.00		23.00
L2	13.20		14.10
L3	10.55		10.85
L4	2.70		3.20
L5	0.85		1.25
L6	7.30		7.50

 Table 8.
 I²PAKFP (TO-281) mechanical data

Figure 19. I²PAKFP (TO-281) drawing





5 Revision history

Table 9.Document revision history

Date	Revision	Changes
13-Apr-2012	1	First release.



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